

## Dual N-Channel Enhancement Mode MOSFET

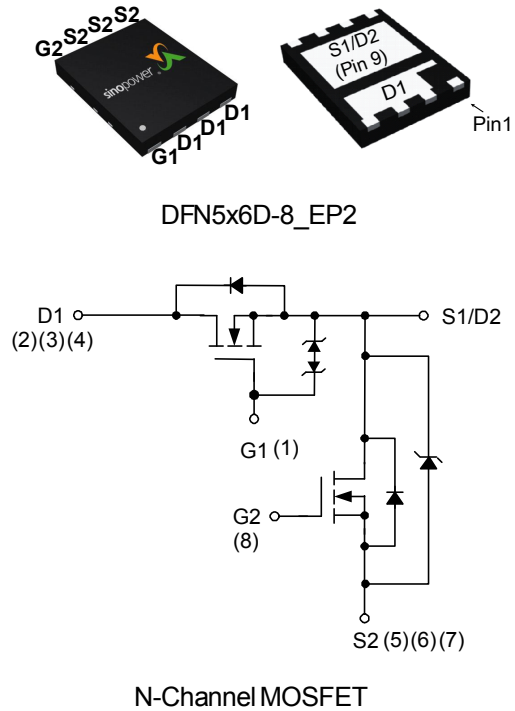
### Features

- Channel 1 (ESD Protection)**  
 30V/83A,  
 $R_{DS(ON)} = 3m\Omega$  (max.) @  $V_{GS} = 10V$   
 $R_{DS(ON)} = 5.6m\Omega$  (max.) @  $V_{GS} = 4.5V$
- Channel 2 (Integrated Schottky diode)**  
 30V/85A,  
 $R_{DS(ON)} = 1.3m\Omega$  (max.) @  $V_{GS} = 10V$   
 $R_{DS(ON)} = 2.0m\Omega$  (max.) @  $V_{GS} = 4.5V$
- 100% UIS +  $R_g$  Tested
- Dual Dies Package and Minimize Board Space
- Lower  $Q_g$  and  $Q_{gd}$  for High-Speed Switching
- Lower  $R_{DS(ON)}$  to Minimize Conduction Losses
- Reliable and Rugged
- Lead Free Available (RoHS Compliant)


### Applications

- Power Management in Desktop Computer or DC/DC Converters.

### Pin Description



### Ordering and Marking Information

<p>SM7360EK □□□-□□□</p> <p>             □□□□ — Assembly Material              □□□□ — Handling Code              □□□□ — Temperature Range              □□□□ — Package Code         </p>	<p>Package Code QG : DFN5x6D-8_EP2</p> <p>Operating Junction Temperature Range C : -55 to 150 °C</p> <p>Handling Code TR : Tape &amp; Reel</p> <p>Assembly Material G : Halogen and Lead Free Device</p>
<p>SM7360EK QG : </p>	<p>XXXXX - Lot Code</p>

Note : SINOPOWER lead-free products contain molding compounds/die attach materials and 100% matte tin plate termination finish; which are fully compliant with RoHS. SINOPOWER lead-free products meet or exceed the lead-free requirements of IPC/JEDEC J-STD-020D for MSL classification at lead-free peak reflow temperature. SINOPOWER defines “Green” to mean lead-free (RoHS compliant) and halogen free (Br or Cl does not exceed 900ppm by weight in homogeneous material and total of Br and Cl does not exceed 1500ppm by weight).

SINOPOWER reserves the right to make changes to improve reliability or manufacturability without notice, and advise customers to obtain the latest version of relevant information to verify before placing orders.

## Absolute Maximum Ratings ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Channel 1	Channel 2	Unit	
<b>Common Ratings</b>					
$V_{DSS}$	Drain-Source Voltage	30		V	
$V_{GSS}$	Gate-Source Voltage	$\pm 20$		V	
$T_J$	Maximum Junction Temperature	150		$^\circ\text{C}$	
$T_{STG}$	Storage Temperature Range	-55 to 150		$^\circ\text{C}$	
$I_S$	Diode Continuous Forward Current	30	75	A	
$I_D$	Continuous Drain Current	$T_C=25^\circ\text{C}$	83	$85^a$	A
		$T_C=100^\circ\text{C}$	52	$85^a$	
$I_{DM}^b$	Pulse Drain Current Tested	$T_C=25^\circ\text{C}$	200	300	A
$P_D$	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	35	83	W
		$T_C=100^\circ\text{C}$	14	33	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	3.5	1.5	$^\circ\text{C}/\text{W}$
$I_D$	Continuous Drain Current	$T_A=25^\circ\text{C}$	17	25	A
		$T_A=70^\circ\text{C}$	13.6	20	
$P_D$	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	1.38	1.38	W
		$T_A=70^\circ\text{C}$	0.88	0.88	
$R_{\theta JA}^c$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$	45	41	$^\circ\text{C}/\text{W}$
		Steady State	90	90	
$I_{AS}^d$	Avalanche Current, Single pulse ( $L=0.1\text{mH}$ )	30	50	A	
$E_{AS}^d$	Avalanche Energy, Single pulse ( $L=0.1\text{mH}$ )	45	125	mJ	

Note a: Package is limited to 85A.

Note b: Pulse width is limited by max. junction temperature.

Note c: Surface mounted on  $1\text{in}^2$  pad area, steady state  $t=999\text{s}$ .

Note d: UIS tested and pulse width are limited by maximum junction temperature  $150^\circ\text{C}$  (initial temperature  $T_J=25^\circ\text{C}$ ).

## Channel 1 Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Channel 1			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	30	-	-	V
BV <sub>DSSst</sub>	Drain-Source Breakdown Voltage (transient)	V <sub>GS</sub> =0V, I <sub>D(aval)</sub> =30A T <sub>case</sub> =25°C, t <sub>transient</sub> =100ns	34	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V T <sub>J</sub> =85°C	-	-	1	μA
			-	-	30	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250μA	1.4	1.7	2.5	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±10	μA
R <sub>DS(ON)</sub> <sup>e</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =13A T <sub>J</sub> =125°C	-	2.5	3	mΩ
			-	3.6	-	
		V <sub>GS</sub> =4.5V, I <sub>DS</sub> =11A	-	4.2	5.6	
G <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =11A	-	22	-	S
<b>Diode Characteristics</b>						
V <sub>SD</sub> <sup>e</sup>	Diode Forward Voltage	I <sub>SD</sub> =13A, V <sub>GS</sub> =0V	-	0.8	1.1	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>DS</sub> =13A, dI <sub>SD</sub> /dt=100A/μs V <sub>DD</sub> =15V	-	33	-	ns
t <sub>a</sub>	Charge Time		-	16	-	
t <sub>b</sub>	Discharge Time		-	17	-	
Q <sub>rr</sub>	Reverse Recovery Charge		-	19	-	
<b>Dynamic Characteristics<sup>f</sup></b>						
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, F=1MHz	-	0.9	1.8	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, Frequency=1.0MHz	-	1200	1560	pF
C <sub>oss</sub>	Output Capacitance		-	770	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	60	-	
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DD</sub> =15V, R <sub>L</sub> =15Ω, I <sub>DS</sub> =1A, V <sub>GEN</sub> =10V, R <sub>G</sub> =1Ω	-	8.8	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	10.6	-	
t <sub>d(OFF)</sub>	Turn-off Delay Time		-	22	-	
t <sub>f</sub>	Turn-off Fall Time		-	29	-	
<b>Gate Charge Characteristics<sup>f</sup></b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>DS</sub> =13A	-	9.3	-	nC
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>DS</sub> =13A	-	19	-	
Q <sub>gth</sub>	Threshold Gate Charge		-	1.3	-	
Q <sub>gs</sub>	Gate-Source Charge		-	2	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	4.3	-	

Note e: Pulse test ; pulse width≤300μs, duty cycle≤2%.

Note f: Guaranteed by design, not subject to production testing.

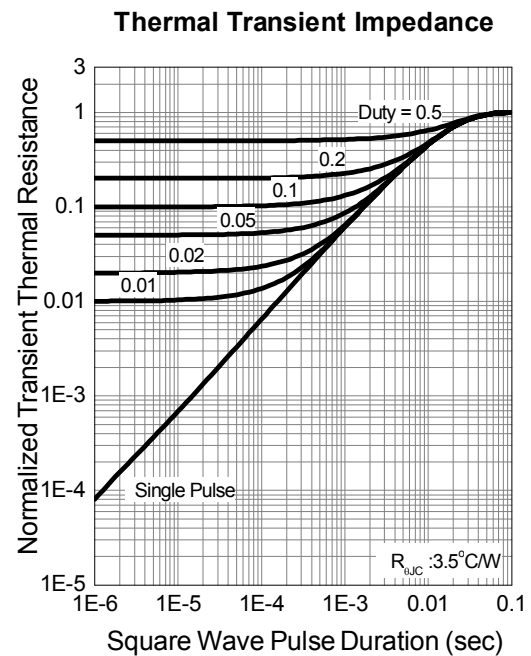
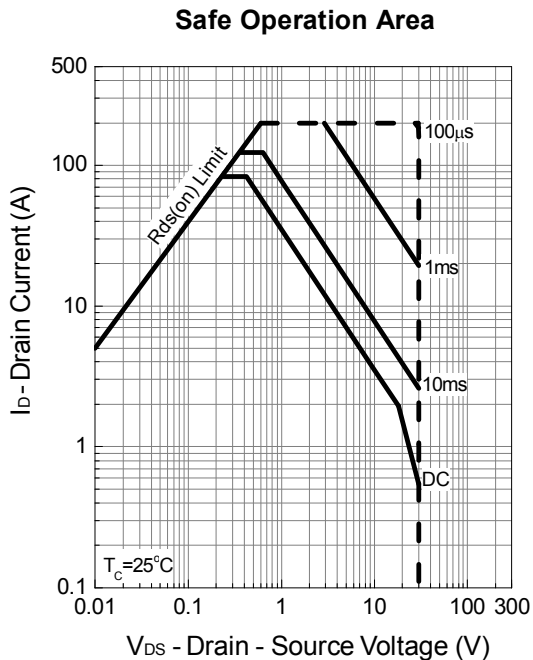
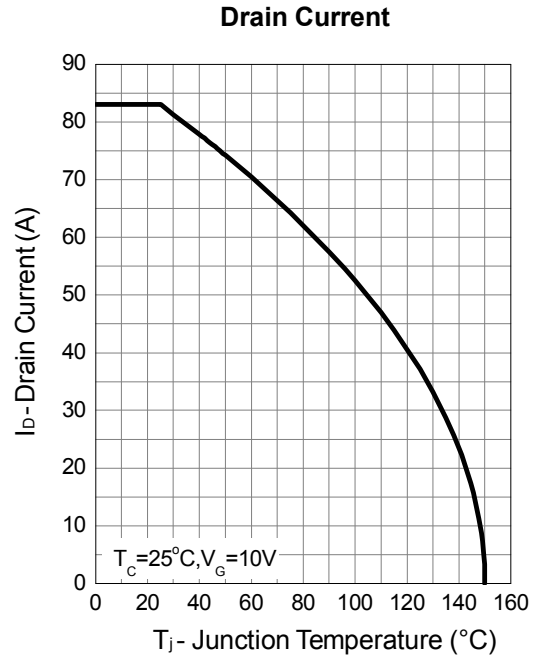
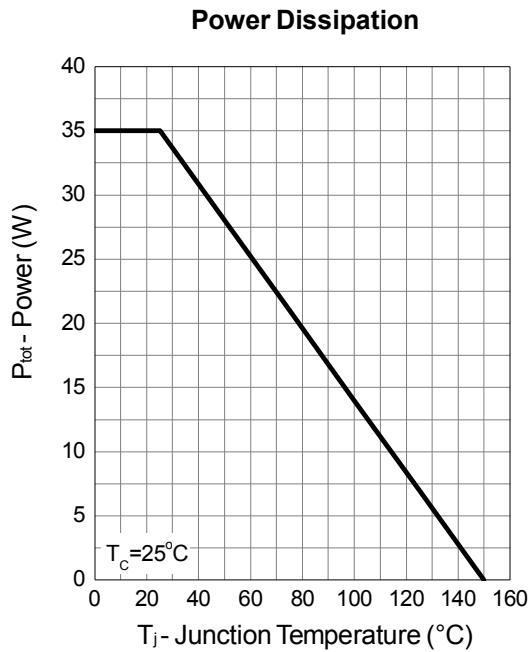
## Channel 2 Electrical Characteristics (T<sub>A</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Channel 2			Unit
			Min.	Typ.	Max.	
<b>Static Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =250μA	30	-	-	V
BV <sub>DSS(t)</sub>	Drain-Source Breakdown Voltage (transient)	V <sub>GS</sub> =0V, I <sub>D(aval)</sub> =50A T <sub>case</sub> =25°C, t <sub>transient</sub> =100ns	34	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =24V, V <sub>GS</sub> =0V	-	-	500	μA
		T <sub>J</sub> =85°C	-	-	5	mA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>DS</sub> =250μA	1.4	1.7	2.5	V
I <sub>GSS</sub>	Gate Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
R <sub>DS(ON)</sub> <sup>e</sup>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =25A	-	1	1.3	mΩ
		T <sub>J</sub> =125°C	-	1.5	-	
		V <sub>GS</sub> =4.5V, I <sub>DS</sub> =20A	-	1.5	2.0	
Gfs	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>DS</sub> =20A	-	50	-	S
<b>Diode Characteristics</b>						
V <sub>SD</sub> <sup>e</sup>	Diode Forward Voltage	I <sub>SD</sub> =2A, V <sub>GS</sub> =0V	-	0.45	0.7	V
		I <sub>SD</sub> =25A, V <sub>GS</sub> =0V	-	0.75	1.1	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>DS</sub> =5A, dI <sub>SD</sub> /dt=100A/μs V <sub>DD</sub> =18V	-	55	-	ns
t <sub>a</sub>	Charge Time		-	30	-	
t <sub>b</sub>	Discharge Time		-	25	-	
Q <sub>rr</sub>	Reverse Recovery Charge		-	64	-	
<b>Dynamic Characteristics<sup>f</sup></b>						
R <sub>G</sub>	Gate Resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, F=1MHz	-	0.7	1.5	Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =15V, Frequency=1.0MHz	-	4450	-	pF
C <sub>oss</sub>	Output Capacitance		-	2050	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	210	-	
t <sub>d(ON)</sub>	Turn-on Delay Time	V <sub>DD</sub> =15V, R <sub>L</sub> =15Ω, I <sub>DS</sub> =1A, V <sub>GEN</sub> =10V, R <sub>G</sub> =1Ω	-	20	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	12.2	-	
t <sub>d(OFF)</sub>	Turn-off Delay Time		-	42	-	
t <sub>f</sub>	Turn-off Fall Time		-	30	-	
<b>Gate Charge Characteristics<sup>f</sup></b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =4.5V, I <sub>DS</sub> =25A	-	29	-	nC
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V, I <sub>DS</sub> =25A	-	63	-	
Q <sub>g(th)</sub>	Threshold Gate Charge		-	7	-	
Q <sub>gs</sub>	Gate-Source Charge		-	12.3	-	
Q <sub>gd</sub>	Gate-Drain Charge	-	6.1	-		

Note e: Pulse test ; pulse width ≤ 300μs, duty cycle ≤ 2%.

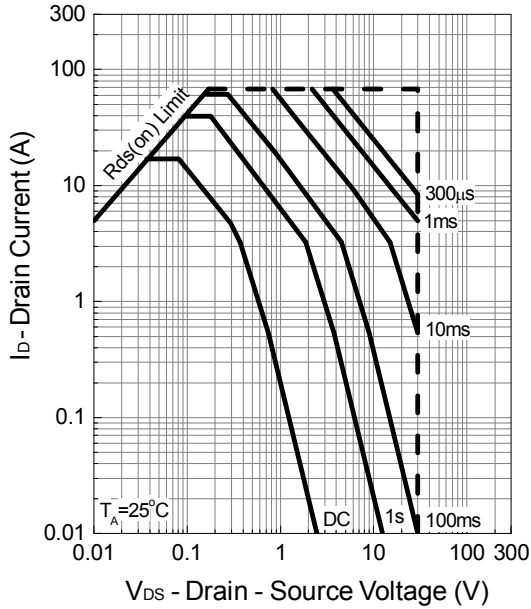
Note f: Guaranteed by design, not subject to production testing.

## Channel 1 Typical Operating Characteristics

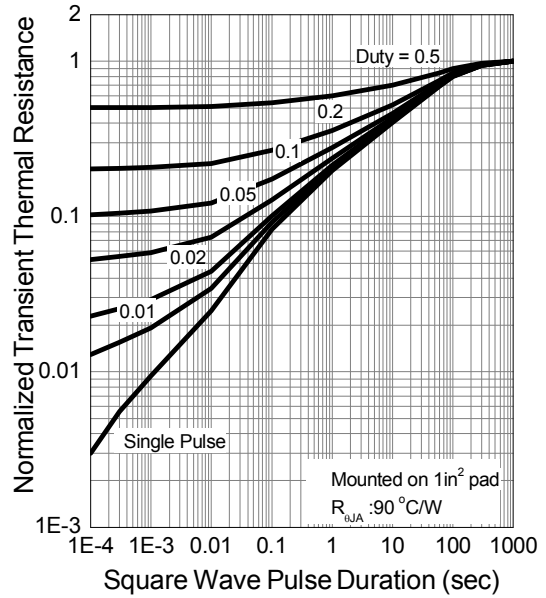


Channel 1 Typical Operating Characteristics (Cont.)

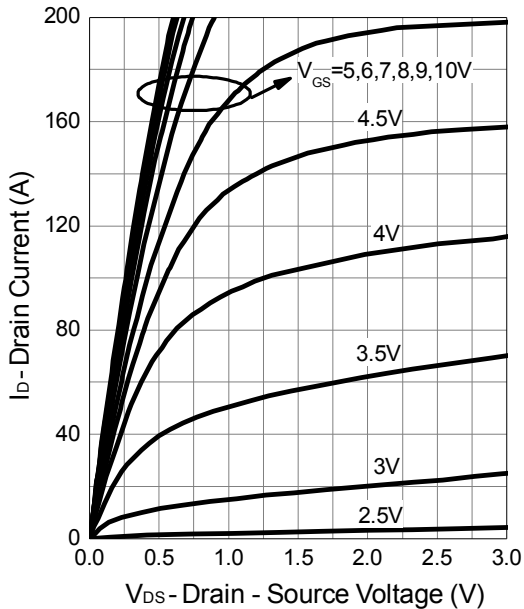
Safe Operation Area



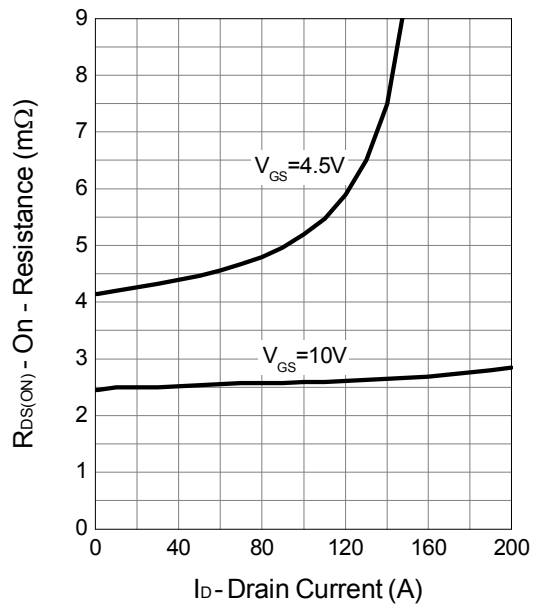
Thermal Transient Impedance



Output Characteristics

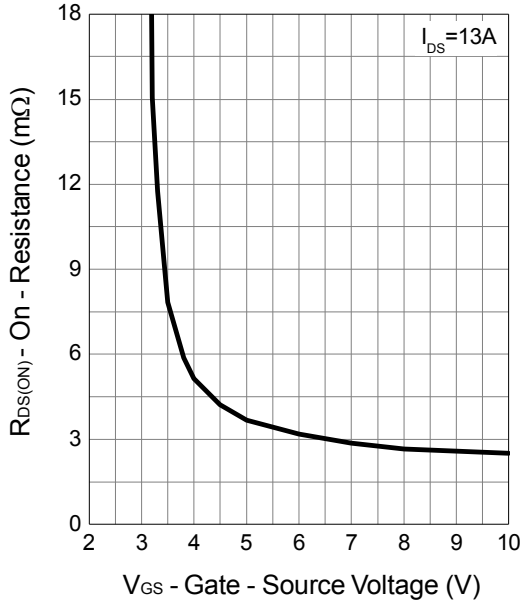


Drain-Source On Resistance

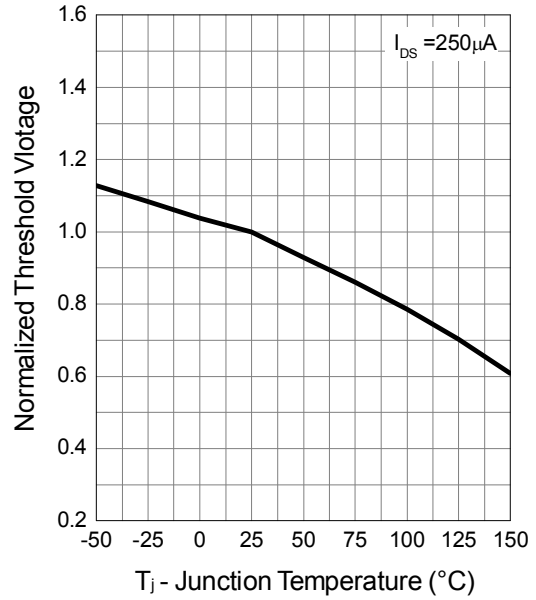


Channel 1 Typical Operating Characteristics (Cont.)

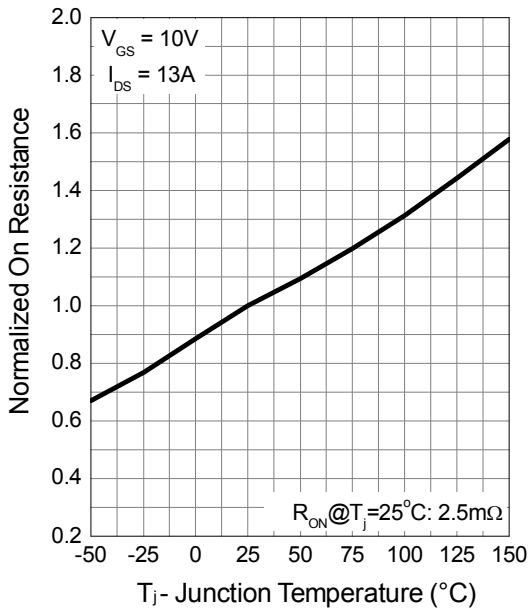
Gate-Source On Resistance



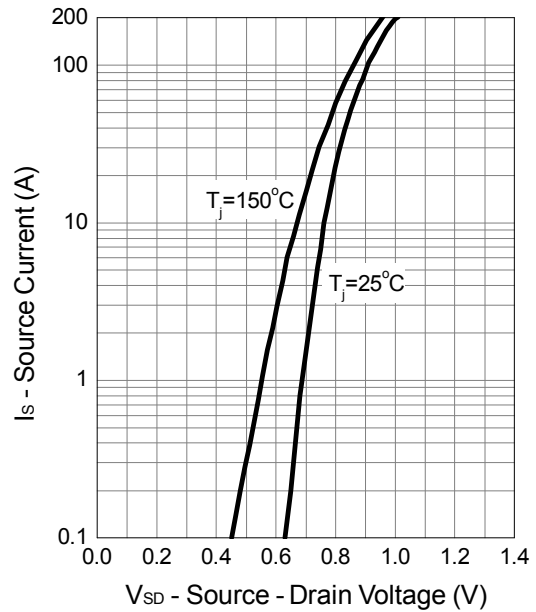
Gate Threshold Voltage



Drain-Source On Resistance

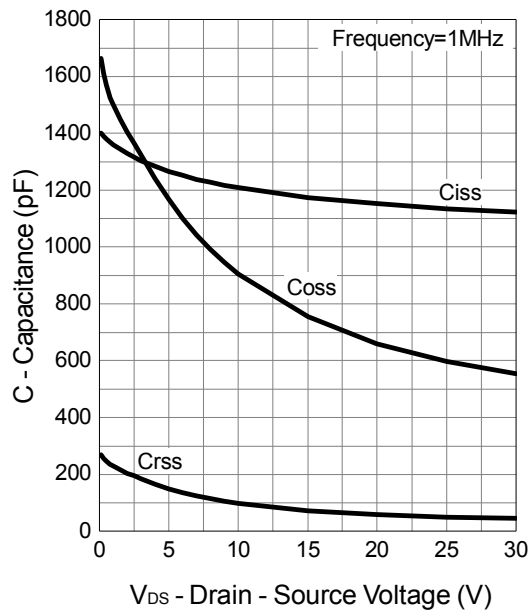


Source-Drain Diode Forward

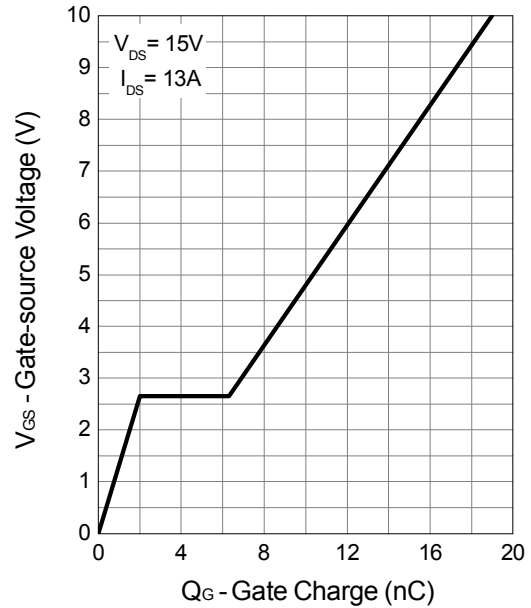


**Channel 1 Typical Operating Characteristics (Cont.)**

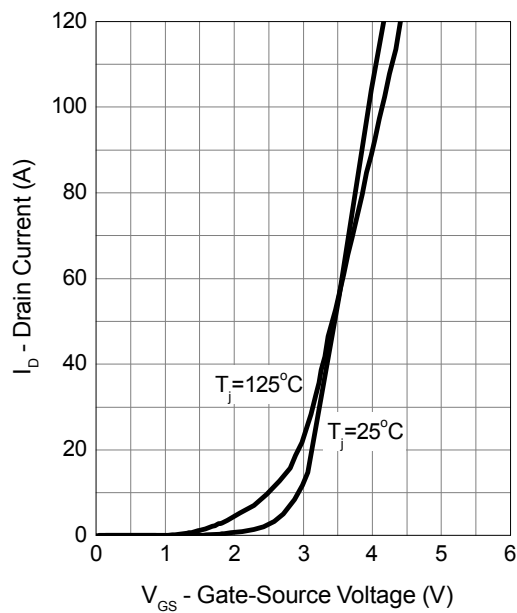
**Capacitance**



**Gate Charge**

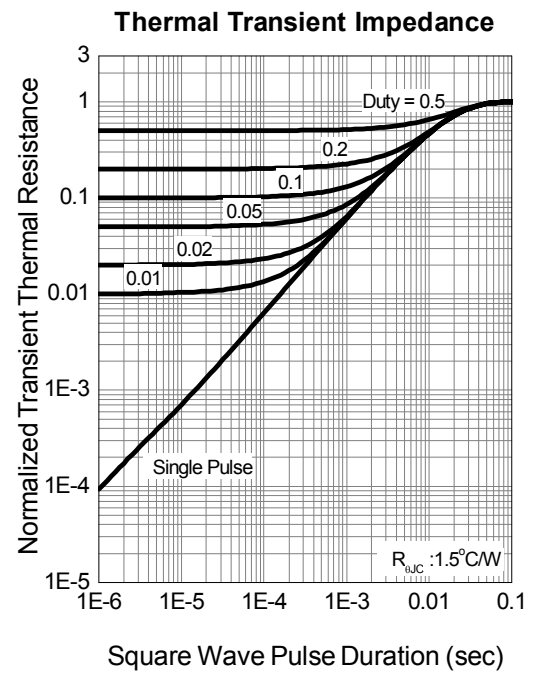
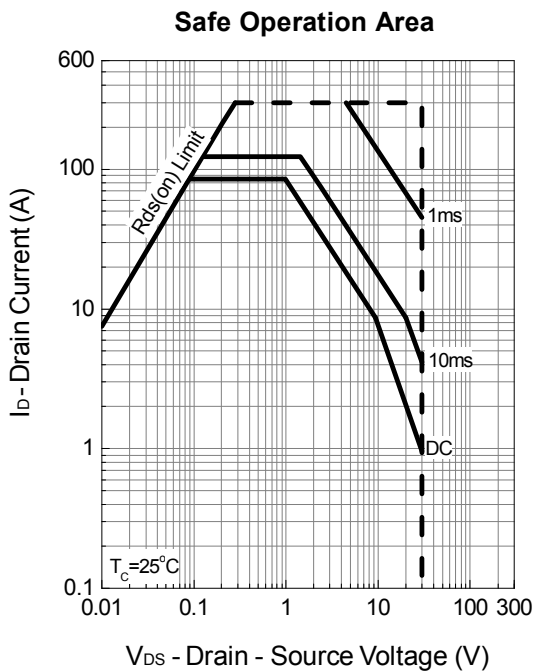
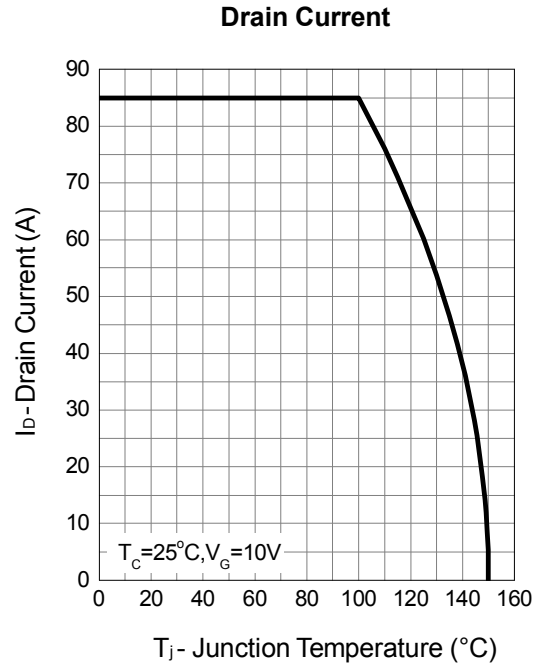
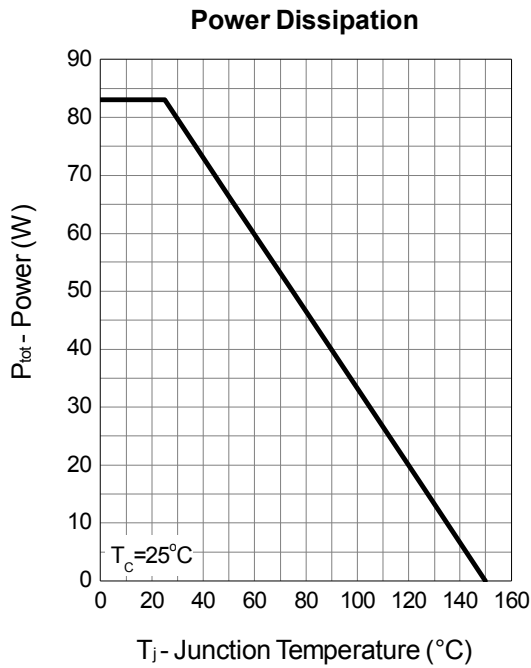


**Transfer Characteristics**

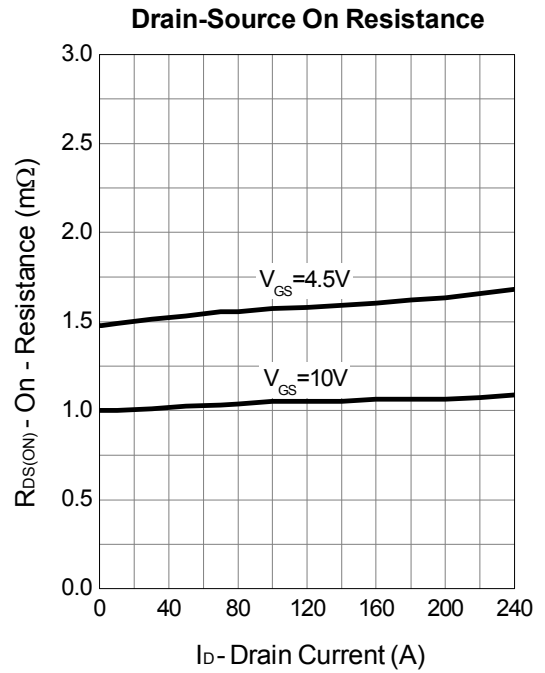
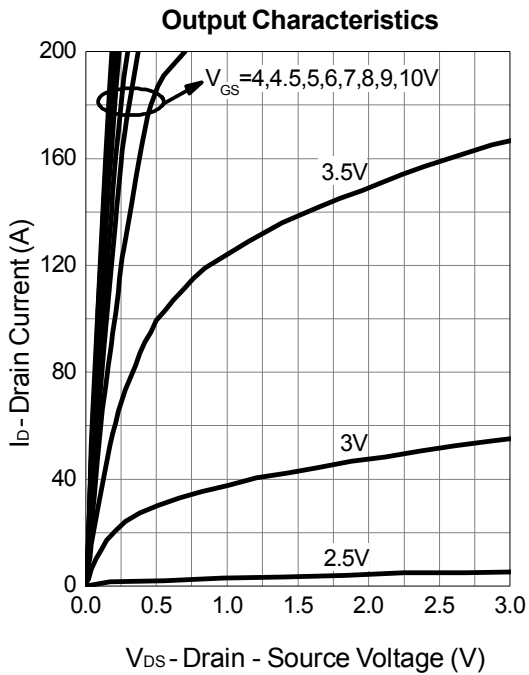
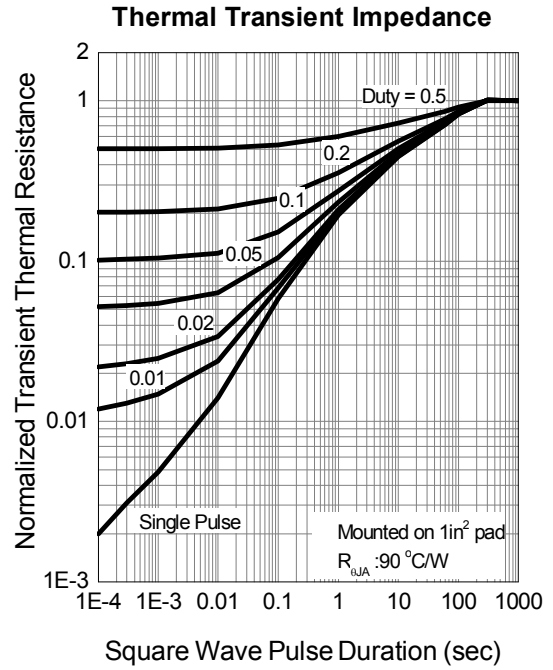
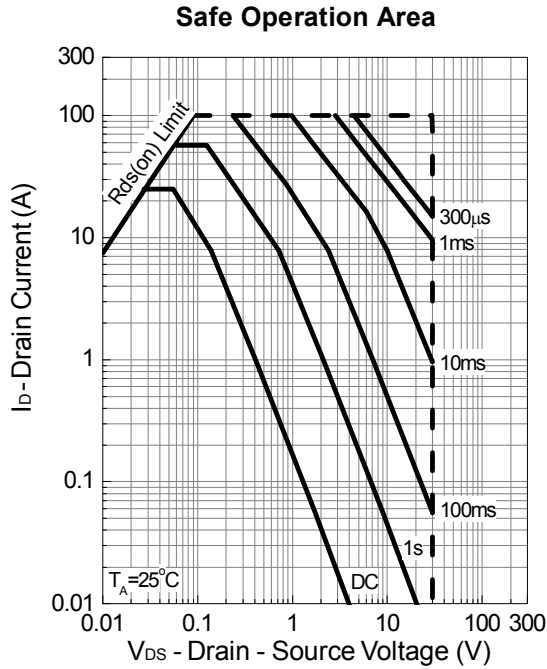




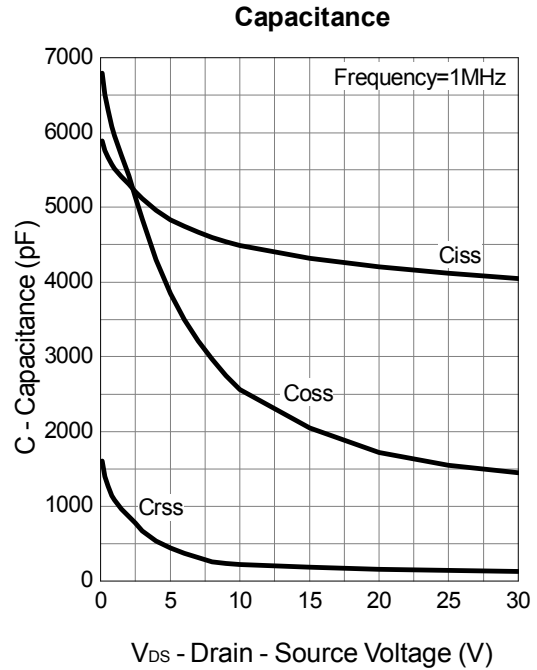
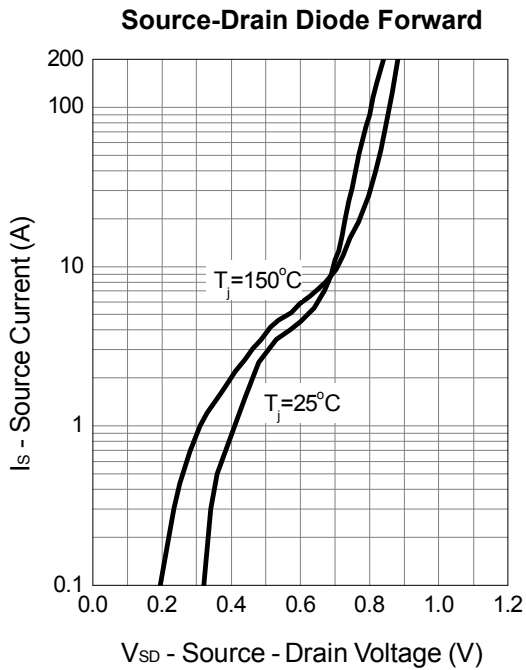
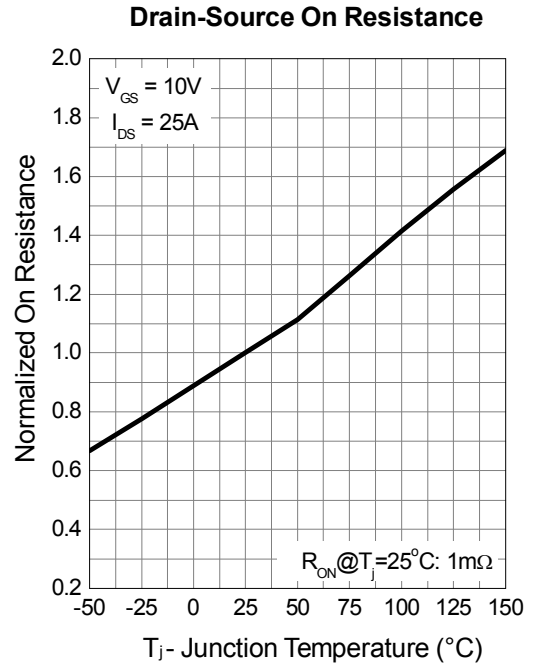
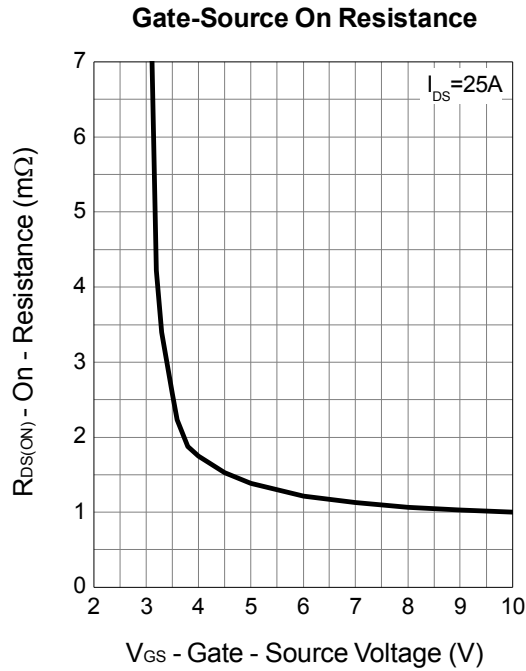
## Channel 2 Typical Operating Characteristics



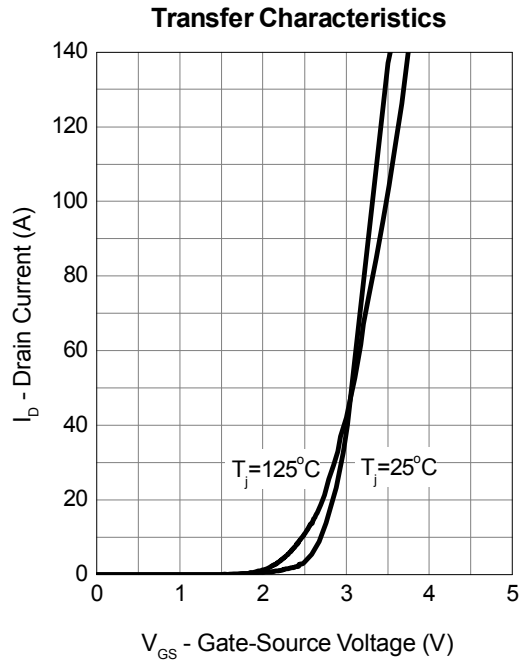
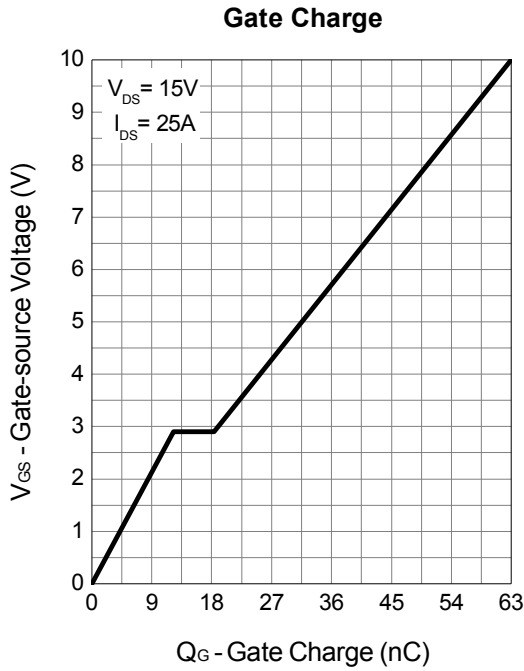
Channel 2 Typical Operating Characteristics (Cont.)



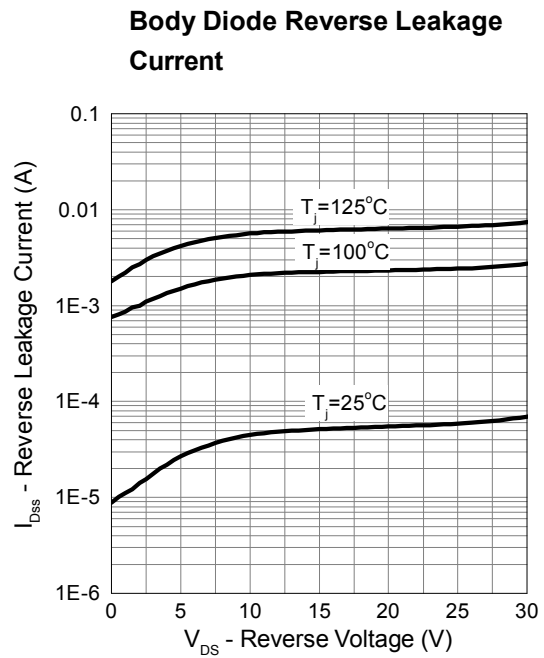
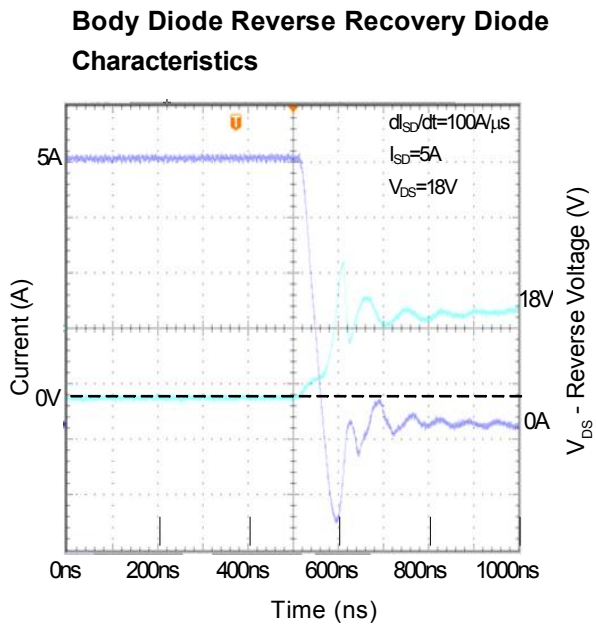
Channel 2 Typical Operating Characteristics (Cont.)



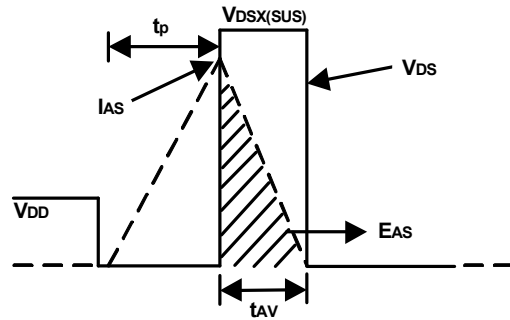
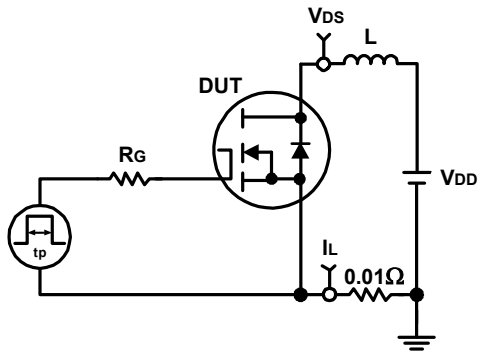
## Channel 2 Typical Operating Characteristics (Cont.)



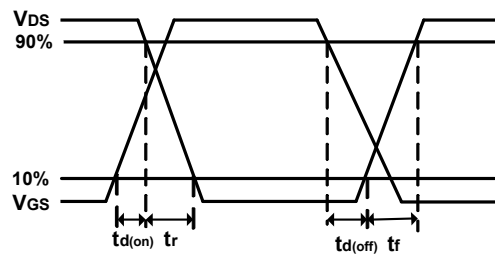
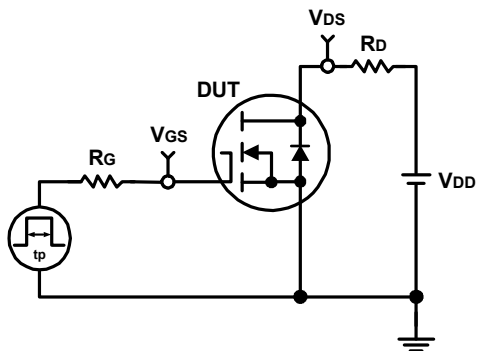
## Channel 2 Schottky Body Diode Characteristics



### Avalanche Test Circuit and Waveforms



### Switching Time Test Circuit and Waveforms



## Disclaimer

Sinopower Semiconductor, Inc. (hereinafter “Sinopower”) has been making great efforts to development high quality and better performance products to satisfy all customers’ needs. However, a product may fail to meet customer’s expectation or malfunction for various situations.

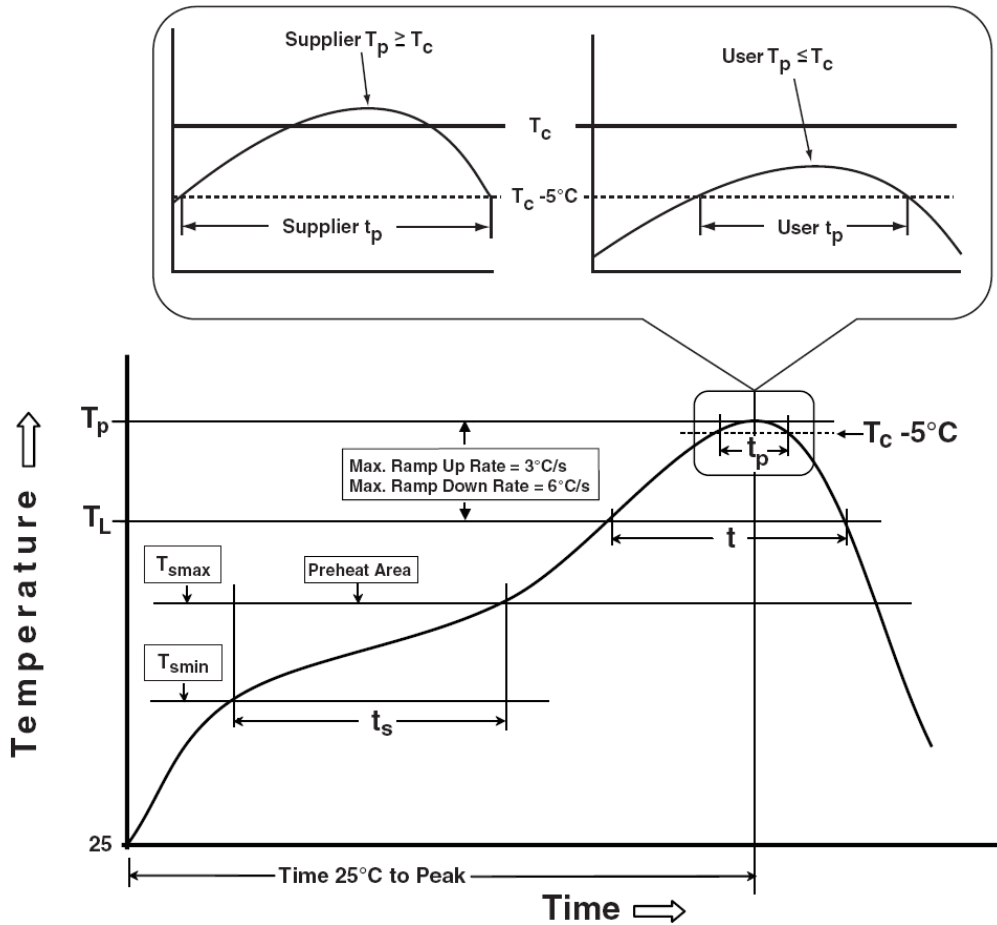
All information which is shown in the datasheet is based on Sinopower’s research and development result, therefore, Sinopower shall reserve the right to adjust the content and monitor the production.

In order to unify the quality and performance, Sinopower has been following JEDEC while defines assembly rule. Notwithstanding all the suppliers basically follow the rule for each product, different processes may cause slightly different results.

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Classification Profile



## Classification Reflow Profiles

Profile Feature	Sn-Pb Eutectic Assembly	Pb-Free Assembly
<b>Preheat &amp; Soak</b>		
Temperature min ( $T_{smin}$ )	100 °C	150 °C
Temperature max ( $T_{smax}$ )	150 °C	200 °C
Time ( $T_{smin}$ to $T_{smax}$ ) ( $t_s$ )	60-120 seconds	60-120 seconds
Average ramp-up rate ( $T_{smax}$ to $T_p$ )	3 °C/second max.	3°C/second max.
Liquidous temperature ( $T_L$ )	183 °C	217 °C
Time at liquidous ( $t_L$ )	60-150 seconds	60-150 seconds
Peak package body Temperature ( $T_p$ )*	See Classification Temp in table 1	See Classification Temp in table 2
Time ( $t_p$ )** within 5°C of the specified classification temperature ( $T_c$ )	20** seconds	30** seconds
Average ramp-down rate ( $T_p$ to $T_{smax}$ )	6 °C/second max.	6 °C/second max.
Time 25°C to peak temperature	6 minutes max.	8 minutes max.
* Tolerance for peak profile Temperature ( $T_p$ ) is defined as a supplier minimum and a user maximum.		
** Tolerance for time at peak profile temperature ( $t_p$ ) is defined as a supplier minimum and a user maximum.		

Table 1. SnPb Eutectic Process – Classification Temperatures ( $T_c$ )

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> ≥350
<2.5 mm	235 °C	220 °C
≥2.5 mm	220 °C	220 °C

Table 2. Pb-free Process – Classification Temperatures ( $T_c$ )

Package Thickness	Volume mm <sup>3</sup> <350	Volume mm <sup>3</sup> 350-2000	Volume mm <sup>3</sup> >2000
<1.6 mm	260 °C	260 °C	260 °C
1.6 mm – 2.5 mm	260 °C	250 °C	245 °C
≥2.5 mm	250 °C	245 °C	245 °C

## Reliability Test Program

Test item	Method	Description
SOLDERABILITY	JESD-22, B102	5 Sec, 245°C
HTRB	JESD-22, A108	1000 Hrs, 80% of VDS max @ $T_{jmax}$
HTGB	JESD-22, A108	1000 Hrs, 100% of VGS max @ $T_{jmax}$
PCT	JESD-22, A102	168 Hrs, 100%RH, 2atm, 121°C
TCT	JESD-22, A104	500 Cycles, -65°C~150°C

## Customer Service

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